

XF Product family

Near-Field Probes 30 MHz up to 6 GHz



Short description

The XF family consists of 5 passive magnetic field probes and 3 passive E field probes designed for measuring magnetic and E-fields in ranges from 30 MHz to 6 GHz during the development phase. Due to their integrated impedance matching the probes are less sensitive in the lower frequency range than the RF type probes. With its broad frequency spectrum and large to very small probe heads, the set covers a wide range of application. An individual probe set can be compiled according to any individual customer's need. The probe heads of the XF family allow for the step by step identification of interference sources on an assembly. We recommend firstly, detecting interference sources on assemblies with the larger sensitive probes from a greater distance. Next, using higher resolution probes, the interference sources can be more precisely located. With trained use of the near field probes field orientation and field distribution on the electronic assembly can be detected. The near field probes are small and handy. They have a sheath current attenuation and are electrically shielded. They can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. They have an internal terminating resistance.

Scope of delivery

- 1x XF-E 04s, E-Field Probe 30 MHz up to 6 GHz
- 1x XF-E 09s, E-Field Probe 30 MHz up to 6 GHz
- 1x XF-E 10, E-Field Probe 30 MHz up to 6 GHz
- 1x XF-R 3-1, H-Field Probe 30 MHz up to 6 GHz
- 1x XF-R 100-1, H-Field Probe 30 MHz up to 6 GHz
- 1x XF-R 400-1, H-Field Probe 30 MHz up to 6 GHz
- 1x XF-U 2.5-1, H-Field Probe 30 MHz up to 6 GHz
- 1x XF-B 3-1, H-Field Probe 30 MHz up to 6 GHz
- 1x SMA-SMA 1 m, SMA-SMA Measuring Cable
- 1x Case CN, System Case Near-Field Probes

Technical parameters

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| Frequency range | 30 MHz ... 6 GHz |
| Connector | SMA, male, jack |